

## ***Advanced Tools for Nanoscopic Materials Characterization***

**(ATNMC2015)**

**November, 5 – 6, 2015**

**Organized by:**

S. N. Bose National Centre for Basic Sciences, Block – JD, Sec – III, Salt lake, Kolkata – 700098  
& Icon Analytical Equipment Pvt. Ltd.

***Venue: Silver Jubilee hall***

***Date: 05/11/2015 Registration: 09:00-9:30***

9.30-10.00	10:00-11:00	11:00—11.30	11.30-12.30	12.30-13.30	13.30-14:30	14:30-15:30	15:30-16:30	16:30-18.00
Inauguration	AKR	High tea	KM	NR	Lunch	VJ	DP	Tea and Visit to facilities

### **Speakers and topics:**

Name	Affiliation	Topic
Dr. A.K.Raychaudhuri (AKR)	SNBNCBS,India	Nanolithography and Nanofabrication using Dual Beam microscopes
Dr. K. Muraleedharan (KM)	CGCRI,India	TEM of interfaces and grain boundaries
Dr. N. Ravishankar (NR)	IISc,India	TEM of nanomaterials
Dr. Vikram Jayram (VJ)	IISc, India	SEM fundamentals and examples of some advanced applications
Dr. Daniel Phifer (DP)	FEI, Netherlands	Find Answers that change the World with FEI's Latest Innovation in SEM, Dual beam and TEM

**19.00: Conference Diner (Sponsored) , Venue : Lawn of SNBNCBS**

***Date: 06/11/2015***

9:00-10:00	10:00—11.00	11.00-11.15	11.15-12.15	12.15-13:00	13:00-14:00	14:00-15:00	15:00-16:00	16:00-17:00	17:00-17:30
KB	DG	Tea	BG	AG	Lunch	DP	WB	YJ	Tea and concluding session

## **Speakers and topics**

Name	Affiliation	Topic
Dr.Karthik Balasubramaniam (KB)	Icon Analytical, India	Recent Advancement in Transmission Electron Microscopy in Material Science
Dr. Daniel Goran (DG)	Bruker Nano Science Division	Transmission Kikuchi Diffraction in the SEM using OPTIMUS TKD
Dr.Barnali Ghosh (BG)	SNBNCBS, India	Energy Filtered TEM and EELS using TEM
Dr. Ankita Ghatak (AG)	SNBNCBS,India	Simulations of HRTEM images
Dr. Daniel Phifer (DP)	FEI, Netherlands	Fast, Flexible(s) TEM Sample Preparation with Dual Beam Instruments
Dr. Wolfgang Betz (WB)	Physical Electronics (USA)	Applications of 2- AND 3 dimensional analysis on Nanostructured Materials using XPS, Auger and Time of Flight SIMS
Dr. Yogesh Jeyaram (YJ)	Bruker, India	Recent advancement on Atomic Force Microscopy and applications in Nano Science

For any question or queries please send mail to : [atnmc2015@bose.res.in](mailto:atnmc2015@bose.res.in)

Contact:

Debashree Bhattacharyya: Mobile+919230024380